

CALL FOR PAPERS
Design, Technology, and Test of Integrated Circuits and Systems
Journal of Circuits, Systems and Computers
Special Issue

Journal of Circuits, Systems and Computers seeks original manuscripts for a Special Issue/Section on **Design, Technology, and Test of Integrated Circuits and Systems**, scheduled to appear in an issue of 2019.

One of the main challenges for the electronic research field is to cope with the rapidly progressing technology which, today, reaches the nanometer scale. The areas of interest of this Special Issue include the design, test and technology of electronic products, ranging from integrated circuit modules and printed circuit boards to full systems and microsystems, as well as the methodologies and tools used in the design, verification and validation of such products. As a side effect of the process shrinking, classical computing approaches are no more attractive and novel emerging technologies are progressively raising interests to the scientific community, which is actually working on: computing-in-memory architectures, approximate computing, evolvable computing, MRAM devices and so on.

Topics of the Special Issue include, but are not limited to:

Integrated Systems Design:	Integrated Systems Technology:	Integrated Systems Testing:
SOC, SIP design	Computing-in-memory	Nanoelectronics
Multiprocessor systems	Approximate Computing	Device modeling
Embedded systems	Evolvable Computing	Material characterization
Wireless systems	Digital Circuits	Failure analysis
Network on Chip	Analog and RF Circuits	New components
MEMS and MOEMS	Mixed-Signal Circuits	Packaging
Low Voltage and Low Power systems		Process technology
Synthesis (physical, logic)		Reliability issues
3D integration		3D integration
Hardware Security		Emerging Technologies
		Defect and fault modeling
		MEMS/MOEMS testing
		SOC and SIP testing
		Delay testing
		Memory testing
		Fault Simulation, ATPG
		DFT, BIST and BISR
		On-line testing and fault tolerant systems
		ATE issues
		Alternative test strategies
		Security and Safety
		Test of Approximate circuits and systems

Submitted articles must not have been previously published or currently submitted for journal publication elsewhere. As an author, you are responsible for understanding and adhering to our submission guidelines. You can access them at the Journal of Circuits, Systems and Computers submission guidelines. Please thoroughly read these before submitting your manuscript.

Submission deadline: September 30th 2018
 Reviews completed: December 18th 2018
 First round notification: December 20th 2018
 Reviews of revisions: January 31st 2019
 Notification of final acceptance: February 28th, 2019
 Publication materials for final manuscripts due: March 15th 2019
 Publication date: May 31st 2019

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